CAT64LC40/CAT64LC40I

4K-Bit SERIAL E²PROM

FEATURES

- SPI Bus Compatible
- Low Power CMOS Technology
- 2.5V to 5.5V Operation
- Self-Timed Write Cycle with Auto-Clear
- Hardware Reset Pin
- Hardware and Software Write Protection
- Power-Up Inadvertant Write Protection
- RDY/$\overline{\text{BUSY}}$ Pin for End-of-Write Protection
- 100,000 Program/Erase Cycles
- 100 Year Data Retention
- ZERO Power™ (CAT64LC40Z) Version Available
- Optional High Endurance Device Available

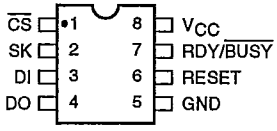
4

DESCRIPTION

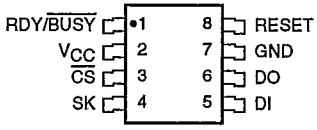
The CAT64LC40 and CAT64LC40I are 4K bit Serial E²PROM memory devices which are configured as 256 registers by 16 bits. Each register can be written (or read) serially by using the DI (or DO) pin. The CAT64LC40/CAT64LC40I is manufactured using Catalyst's advanced CMOS E²PROM floating gate technology. It is designed to endure 100,000 program/erase cycles and has a data retention of 100 years. The device is available in 8 pin DIP or SO packages.

PIN CONFIGURATION

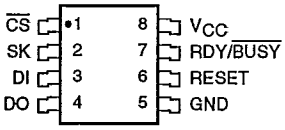
DIP Package



SO Package J



SO Package S

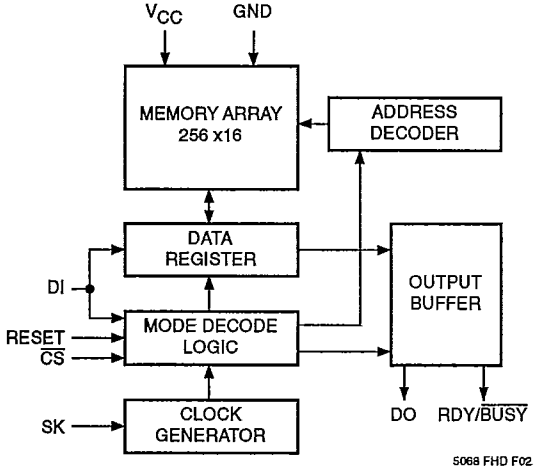


5064 FHD F01

PIN FUNCTIONS

Pin Name	Function
$\overline{CS}$	Chip Select
SK	Clock Input
DI	Serial Data Input
DO	Serial Data Output
V_{CC}	+2.5V to +5.5V Power Supply
GND	Ground
RESET	Reset
RDY/$\overline{BUSY}$	Ready/$\overline{BUSY}$ Status

BLOCK DIAGRAM



5068 FHD F02

TD 5068

ABSOLUTE MAXIMUM RATINGS*

Temperature Under Bias .....–55°C to +125°C

Storage Temperature .....–65°C to +150°C

Voltage on any Pin with Respect to Ground(1) .....–2.0V to +V_{CC} +2.0V

V_{CC} with Respect to Ground .....–2.0V to +7.0V

Package Power Dissipation Capability (Ta = 25°C) 1.0W

Lead Soldering Temperature (10 secs) .....300°C

Output Short Circuit Current(2) .....100 mA

*COMMENT

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions outside of those listed in the operational sections of this specification is not implied. Exposure to any absolute maximum rating for extended periods may affect device performance and reliability.

RELIABILITY CHARACTERISTICS

Symbol	Parameter	Min.	Max.	Units	Reference Test Method
N_{END}(3)	Endurance	100,000		Cycles/Byte	MIL-STD-883, Test Method 1033
T_{DR}(3)	Data Retention	100		Years	MIL-STD-883, Test Method 1008
V_{ZAP}(3)	ESD Susceptibility	2000		Volts	MIL-STD-883, Test Method 3015
I_{LTH}(3)(4)	Latch-Up	100		mA	JEDEC Standard 17

CAPACITANCE (T_A = 25°C, f= 1.0 MHz, V_{CC} = 5.5V)

Symbol	Test	Max.	Units	Conditions
$C_{I/O}$(3)	Input/Output Capacitance (DO, RDY/$\overline{BUSY}$)	8	pF	$V_{I/O}$ = 0V
C_{IN}(3)	Input Capacitance ($\overline{CS}$, SK, DI, RESET)	6	pF	V_{IN} = 0V

Note:
(1) The minimum DC input voltage is –0.5V. During transitions, inputs may undershoot to –2.0V for periods of less than 20 ns. Maximum DC voltage on output pins is V_{CC} +0.5V, which may overshoot to V_{CC} +2.0V for periods of less than 20 ns.
(2) Output shorted for no more than one second. No more than one output shorted at a time.
(3) This parameter is tested initially and after a design or process change that affects the parameter.
(4) Latch-up protection is provided for stresses up to 100 mA on address and data pins from –1V to V_{CC} +1V.

D.C. OPERATING CHARACTERISTICS

CAT64LC40 T_A= 0°C to +70°C, V_{CC} = +2.5V to +5.5V, unless otherwise specified.
CAT64LC40I T_A= –40°C to +85°C, V_{CC} = +2.5V to +5.5V, unless otherwise specified.

Sym.	Parameter		Limits Min.	Typ.	Max.	Units	Test Conditions
I_{CC}	Operating Current	2.5V			0.4	mA	f_{SK} = 250 kHz
	EWEN, EWDS, READ	5.5V			1.0		f_{SK} = 1 MHz
I_{CCP}	Program Current	2.5V			2.0	mA	
		5.5V			3.0		
I_{SB}	Standby Current	Standard			3.0	µA	V_{IN} = GND or V_{CC}
I_{SBZ}(5)		ZERO Pwr™			0		$\overline{CS}$ = V_{CC}
I_{LI}	Input Leakage Current				2.0	µA	V_{IN} = GND to V_{CC}
I_{LO}	Output Leakage Current				10	µA	V_{OUT} = GND to V_{CC}
V_{IL}	Low Level Input Voltage, DI		–0.1		V_{CC} x 0.3	V	
V_{IH}	High Level Input Voltage, DI		V_{CC} x 0.7		V_{CC} + 0.5	V	
V_{IL}	Low Level Input Voltage, $\overline{CS}$, SK, RESET		–0.1		V_{CC} x 0.2	V	
V_{IH}	High Level Input Voltage, $\overline{CS}$, SK, RESET		V_{CC} x 0.8		V_{CC} + 0.5	V	
V_{OH}	High Level Output Voltage	2.5V	V_{CC} – 0.3			V	I_{OH} = –10µA
		4.5V	V_{CC} – 0.3				I_{OH} = –10µA
			2.4				I_{OH} = –400µA
V_{OL}	Low Level Output Voltage	2.5V			0.4	V	I_{OL} = 10µA
		4.5V					I_{OL} = 2.1mA

Note:
(5) Standby Current (I_{SBZ}) = 0µA (<900nA)

A.C. OPERATING CHARACTERISTICS

CAT64LC40 T_A= 0°C to +70°C, V_{CC} = +2.5V to +5.5V, unless otherwise specified.
CAT64LC40I T_A= –40°C to +85°C, V_{CC} = +2.5V to +5.5V, unless otherwise specified.

Symbol	Parameter		Limits Min.	Typ.	Max.	Units
t_{CSS}	$\overline{CS}$ Setup Time		100			ns
t_{CSH}	$\overline{CS}$ Hold Time		100			ns
t_{DIS}	DI Setup Time		200			ns
t_{DIH}	DI Hold Time		200			ns
t_{PD1}	Output Delay to 1				300	ns
t_{PD0}	Output Delay to 0				300	ns
t_{HZ}(6)	Output Delay to High Impendance				500	ns
t_{CSMIN}	Minimum $\overline{CS}$ High Time		250			ns
t_{SKHI}	Minimum SK High Time	2.5V	1000			ns
		4.5V–5.5V	400			
t_{SKLOW}	Minimum SK Low Time	2.5V	1000			ns
		4.5V–5.5V	400			
t_{SV}	Output Delay to Status Valid				500	ns
f_{SK}	Maximum Clock Frequency	2.5V	250			kHz
		4.5V–5.5V	1000			
t_{RESS}	Reset to $\overline{CS}$ Setup Time		0			ns
t_{RESMIN}	Minimum RESET High Time		250			ns
t_{RESH}	RESET to READY Hold Time		0			ns
t_{RC}	Write Recovery		100			ns

POWER-UP TIMING(3)(7)

Symbol	Parameter	Min.	Max.	Units
t_{PUR}	Power-Up to Read Operation		10	µs
t_{PUW}	Power-Up to Program Operation		1	ms

WRITE CYCLE LIMIITS

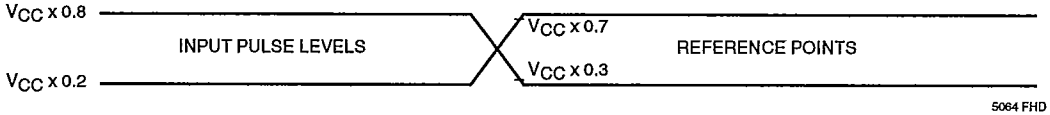
Symbol	Parameter		Min.	Max.	Units
t_{WR}	Program Cycle Time	2.5V		10	ms
		4.5V–5.5V		5	

Note:
(3) This parameter is tested initially and after a design or process change that affects the parameter.
(6) This parameter is sampled but not 100% tested.
(7) t_{PUR} and t_{PUW} are the delays required from the time V_{CC} is stable until the specified operation can be initiated.

INSTRUCTION SET

Instruction	Opcode	Address	Data
Read	10101000	A7 A6 A5 A4 A3 A2 A1 A0	D15–D0
Write	10100100	A7 A6 A5 A4 A3 A2 A1 A0	D15–D0
Write Enable	10100011	XXXXXXXX	
Write Disable	10100000	XXXXXXXX	
[Write All Locations](8)	10100001	XXXXXXXX	D15–D0

Figure 1. A.C. Testing Input/Output Waveform (9)(10)(11) (C_L = 100 pF)



5064 FHD F03

4

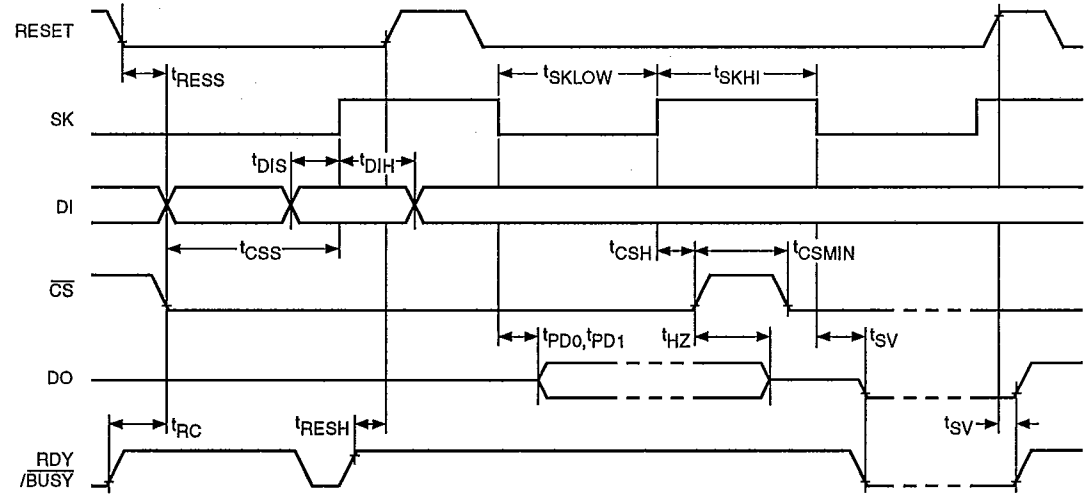
Note:
(8) (Write All Locations) is a test mode operation and is therefore not included in the A.C./D.C. Operations specifications.
(9) Input Rise and Fall Times (10% to 90%) < 10 ns.
(10) Input Pulse Levels = V_{CC} x 0.2 and V_{CC} x 0.8.
(11) Input and Output Timing Reference = V_{CC} x 0.3 and V_{CC} x 0.7.

DEVICE OPERATION

The CAT64LC40/CAT64LC40I is a 4K bit nonvolatile memory intended for use with all standard controllers. The CAT64LC40/CAT64LC40I is organized in a 256 x 16 format. All instructions are based on an 8 bit format. There are four 16 bit instructions: READ, WRITE, EWEN, and EWDS. The CAT64LC40/CAT64LC40I operates on a single power supply ranging from 2.5V to 5.5V and it has an on-chip voltage generator to provide the high voltage needed during a programming operation. Instructions, addresses and data to be written are clocked into the DI pin on the rising edge of the SK clock. The DO pin is normally in a high impedance state except when outputting data in a READ operation or outputting RDY/$\overline{BUSY}$ status when polled during a WRITE operation.

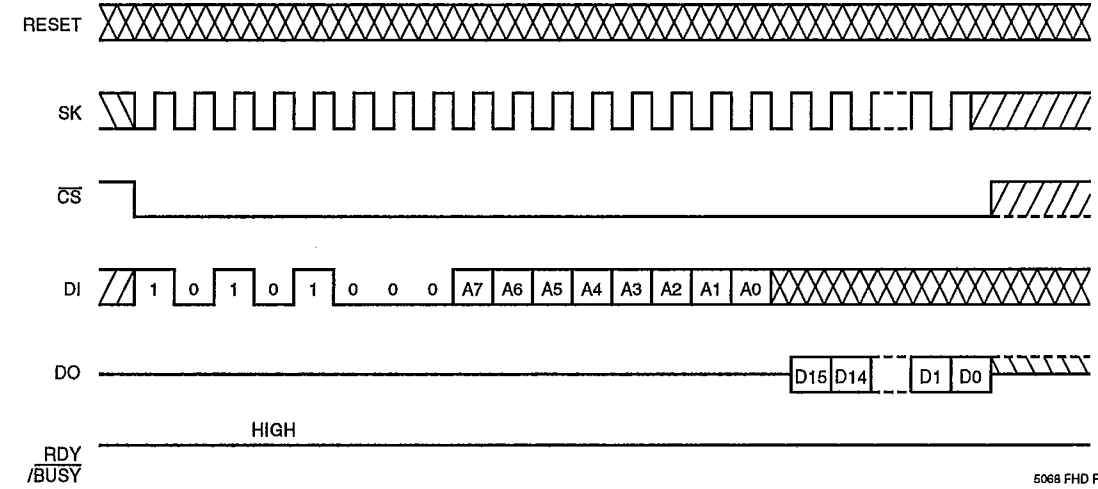
The format for all instructions sent to this device includes a 4 bit start sequence, 1010, a 4 bit op code and an 8 bit address field or dummy bits. For a WRITE operation, a

Figure 2. Sychronous Data Timing



5064 FHD F04

Figure 3. Read Instruction Timing



5068 FHD F05

16 bit data field is also required following the 8 bit address field.

The CAT64LC40/CAT64LC40I requires an active LOW $\overline{CS}$ in order to be selected. Each instruction must be preceded by a HIGH-to-LOW transition of $\overline{CS}$ before the input of the 4 bit start sequence. Prior to the 4 bit start sequence (1010), the device will ignore inputs of all other logical sequence.

Read

Upon receiving a READ command and address (clocked into the DI pin), the DO pin will output data one t_{PD} after the falling edge of the 16th clock (the last bit of the address field). The READ operation is not affected by the RESET input.

Write

After receiving a WRITE op code, address and data, the device goes into the AUTO-Clear cycle and then the

Figure 4. Write Instruction Timing

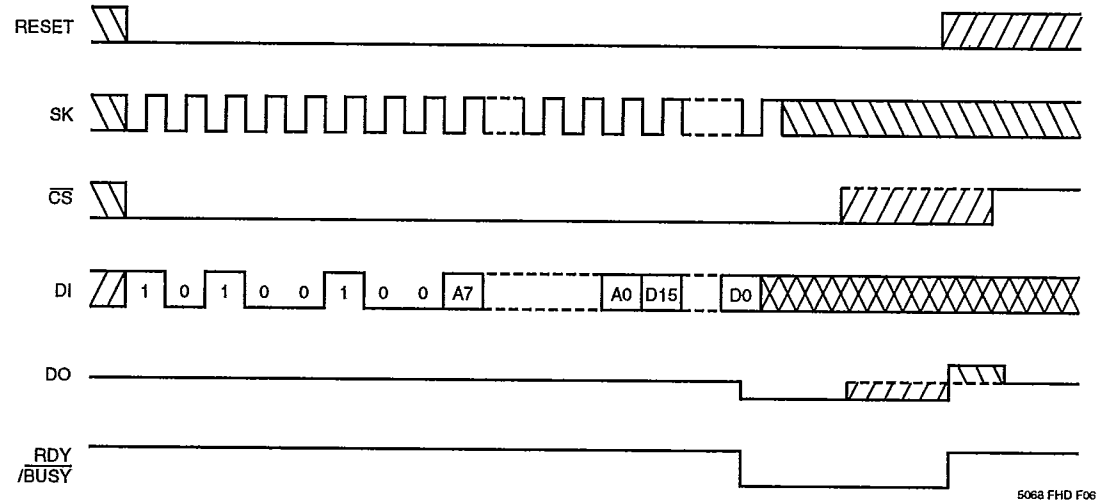
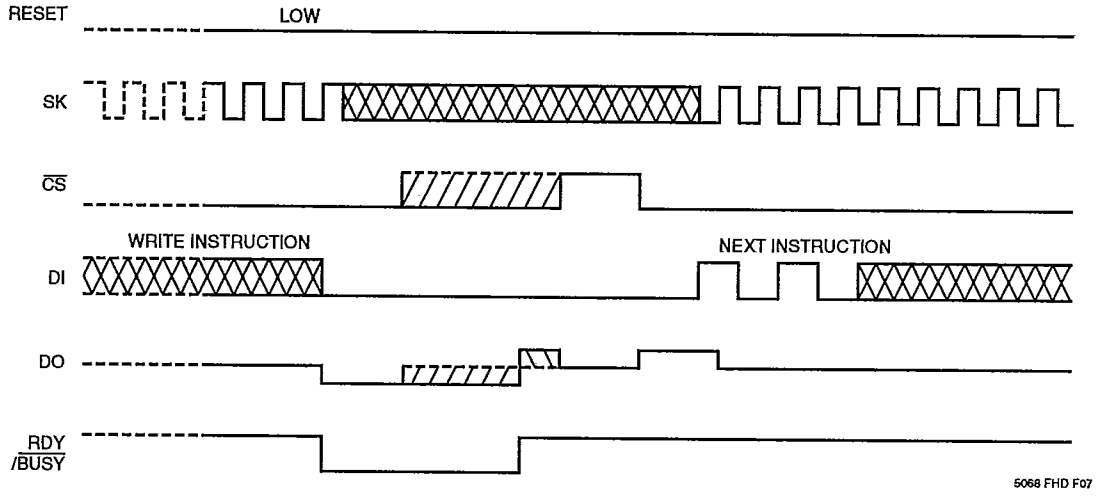


Figure 5. Ready/$\overline{BUSY}$ Status Instruction Timing



WRITE cycle. The RDY/$\overline{BUSY}$ pin will output the $\overline{BUSY}$ status (LOW) one t_{SV} after the rising edge of the 32nd clock (the last data bit) and will stay LOW until the write cycle is complete. Then it will output a logical "1" until the next WRITE cycle. The RDY/$\overline{BUSY}$ output is not affected by the input of $\overline{CS}$.

An alternative to get RDY/$\overline{BUSY}$ status is from the DO pin. During a write cycle, asserting a LOW input to the $\overline{CS}$ pin will cause the DO pin to output the RDY/$\overline{BUSY}$ status. Bringing $\overline{CS}$ HIGH will bring the DO pin back to a high impedance state again. After the device has completed a WRITE cycle, the DO pin will output a logical "1" when the device is deselected. The rising edge of the first "1" input on the DI pin will reset DO back to the high impedance state again.

The WRITE operation can be halted anywhere in the operation by the RESET input. If a RESET pulse occurs during a WRITE operation, the device will abort the operation and output a READY status.

NOTE: Data may be corrupted if a RESET occurs while the device is BUSY. If the reset occurs before the BUSY period, no writing will be initiated. However, if RESET occurs after the BUSY period, new data will have been written over the old data.

Figure 6. RESET During $\overline{BUSY}$ Instruction Timing

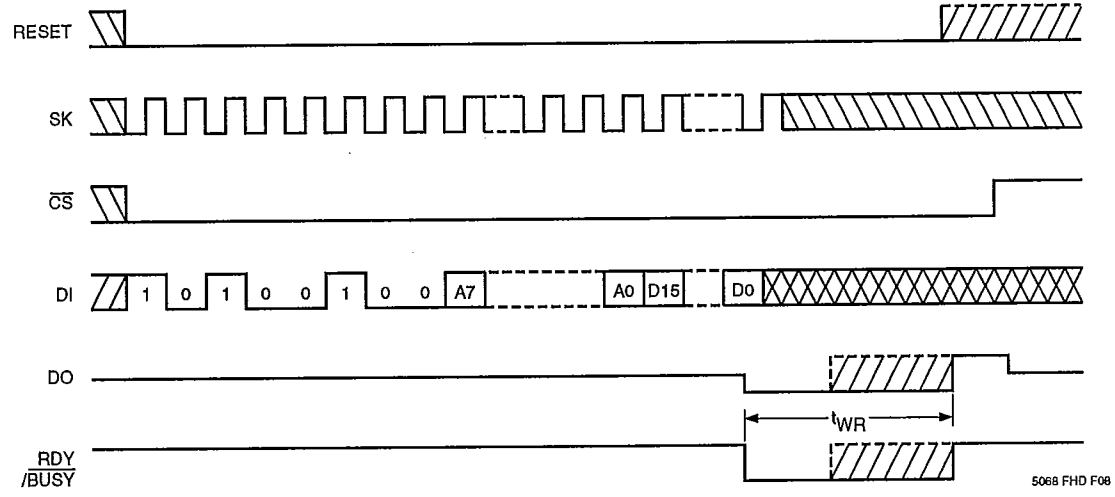
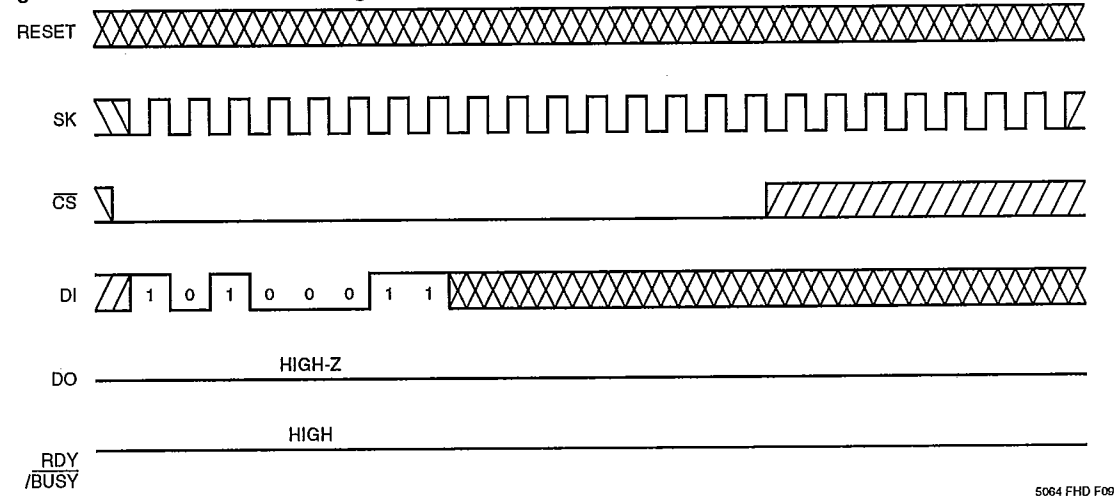


Figure 7. EWEN Instruction Timing



RESET

The RESET pin, when set to HIGH, will reset or abort a WRITE operation. When RESET is set to HIGH while the WRITE instruction is being entered, the device will not execute the WRITE instruction and will keep DO in High-Z condition.

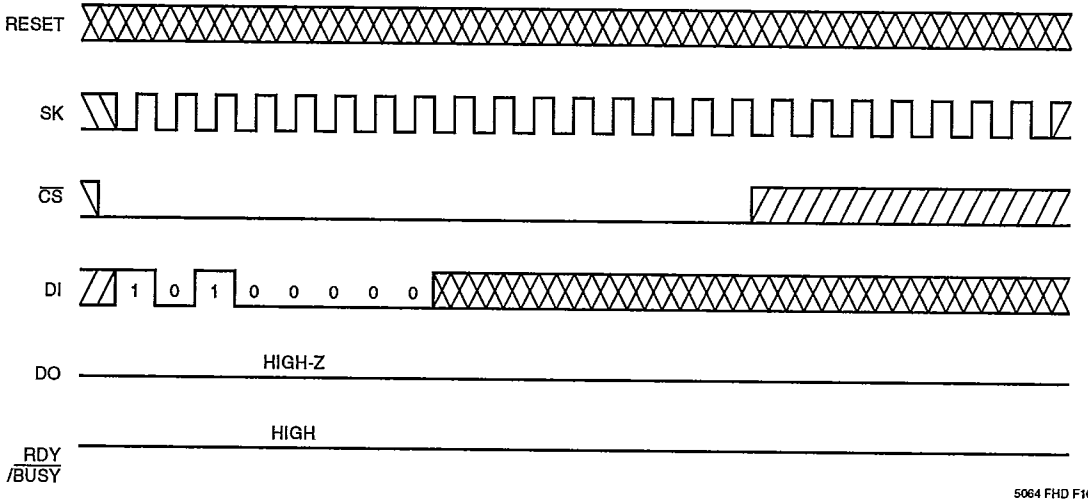
When RESET is set to HIGH, while the device is in a clear/write cycle, the device will abort the operation and will display READY status on the RDY/$\overline{\text{BUSY}}$ pin and on the DO pin if $\overline{\text{CS}}$ is low.

The RESET input affects only the WRITE and WRITE ALL operations. It does not reset any other operations such as READ, EWEN and EWDS.

ERASE/WRITE ENABLE and DISABLE

The CAT64LC40/CAT64LC40I powers up in the erase/write disabled state. After power-up or while the device is in an erase/write disabled state, any write operation must be preceded by an execution of the EWEN instruction. Once enabled, the device will stay enabled until an EWDS has been executed or a power-down has occured. The EWDS is used to prevent any inadvertent overwriting of the data. The EWEN and EWDS instructions have no affect on the READ operation and are not affected by the RESET input.

Figure 8. EWDS Instruction Timing



5064 FHD F10